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UV-VIS-NIR Nd:YAG Laser Line Vertical Mitutoyo Video Microscope Unit

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Stock #71-017 [CONTACT US](#)

⊖ 1 ⊕ £10,000⁰⁰

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Qty 1+	£10,000.00 each
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Note: This item requires accessories for use | [Learn More](#)

Product Downloads

General

378-508 **Model Number:**
UV-VIS-NIR **Range:**
Vertical Mount, Brightfield, Erect Image **Type:**
Manufacturer:

Compatible Objectives:
MPlan Apo/HR/SL, MPlan NIR/NUV, and MPlan UV

Note:
Note: Magnification: 1X Tube Lens Optional C-Mount adapter #37-044 available for dual-camera system

Physical & Mechanical Properties

Weight (g):
1300

Optical Properties

Design Wavelength DWL (nm):
266, 355, 523, 1064nm

Magnification:
1X

Sensor

Maximum Sensor Format:
2/3"

Threading & Mounting

Mount:
C-Mount

Mounting Threads:
Objective Mounts: M26 x 36 TPI

Regulatory Compliance

RoHS 2015:
[Exempt](#)

Certificate of Conformance:
[View](#)

REACH 241:
[Contains SVHC\(s\)](#)

Product Details

- Designed for use with [Mitutoyo NIR, NUV, and UV Infinity Corrected Objectives](#)
- Maximum Sensor Size up to 2/3"
- Ideal for Laser Processing and Machining applications

Mitutoyo Nd:YAG Laser Line Video Microscope Units (VMU) allow for quick and easy setup of laser processing systems by connecting an infinity corrected objective to a c-mount camera. Optimized for Nd:YAG laser lines of 266, 355, 532, and 1064nm, these VMUs are designed for use with [Mitutoyo UV, NUV, and NIR infinity corrected objectives](#). These VMUs can also be used as infrared inspection systems when using an infrared light source and an infrared camera. Mitutoyo Nd:YAG Laser Line Video Microscope Units (VMU) are ideal for laser processing and imaging applications such as cutting, trimming, and repair of IC wiring, thin-film processing, and infrared spectral characteristic analysis. A dual-camera laser line VMU option is also available for high and low magnification observation.